

IEEE Standard Facsimile Test Chart: Bi-level (Black and White)

Sponsor

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Abstract: A facsimile test chart for assessing performance of document facsimile systems, including any compatible combination of facsimile equipment, computers, transmission facilities, and image storage, is provided. The chart is composed solely of high-resolution, high-contrast black-and-white patterns. Although the chart is designed for Group 3 and Group 4 facsimile, it is also expected to be useful in testing other imaging systems. The received image may be recorded or displayed. This standard offers a means of assessing various technical quality parameters, detecting defects produced in received images, and evaluating the readability of text when the original is black and white.

Keywords: facsimile, imaging systems, test charts

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Introduction

[This introduction is not a part of IEEE Std 167A.1-1995, IEEE Standard Facsimile Test Chart: Bi-level (Black and White).]

The purpose of this standard is to provide a means of assessing performance of document facsimile systems, including any compatible combination of facsimile equipments, computers, transmission facilities, and image storage. The advancing technology of document facsimile demands new testing requirements, leading to this revision of IEEE Std 167A-1987. Conflicting test chart reproduction requirements—very high-resolution black-and-white test chart patterns vs. high-quality continuous tone gray scale—are very difficult to satisfy in one test chart at a reasonable cost. Therefore, this standard test chart has no continuous tone content, and is composed solely of high resolution, high contrast black-white patterns. Although the standard test chart is designed for Group 3 and Group 4 facsimile, it is also expected to be useful in testing other imaging systems. The received image may be recorded or displayed.

This standard offers a means of assessing various technical quality parameters, detecting defects produced in received images, and evaluating the readability of text when the original is black and white.

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